

A Complete Bibliography of Publications in *Technometrics* for the decade 1970–1979

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0.5 [Lad77]. 18 [Joh73a]. 2 [BN72]. 2^m [SC71]. 2^n [Joh79]. 2^{n-k} [Joh79]. 2×2 [MDM77]. 3 [Lin79]. 3^n [Hok74]. 4 [Dic74]. 5 [Dic74]. n [TW70]. A [Bad70, Bor72]. α [AS73, McC78a]. $A \subset B$ [Bad70, Bor72]. B [Bad70, Bor72]. β [AS73, GPU76]. C_P [Mal73, Ano73i, Ken71]. D [GK77a, Luc78, Mit74a, Mit74b, MB78a, MB78b, NGM70, SD75]. F [DW72, DW73, HH77, J.79u, Joh73b, Obe77, Pap72, PW72, HB71]. k [HP73, Ode71, WK71, Zei73]. $\log Y$ [Scl72]. m [FM77, HP73]. $m \leq 6$ [SC71]. N [Shu71, Gre70b, Sap73]. $n = 92$ [Wat70a]. O [MHL74]. p [Dun78a, FM77, For72, Lad77, MC72]. $P(Y < X)$ [KKS76]. $P[Y < X]$ [WK77]. $\Pr(Y < X)$ [Dow73]. $\Pr\{Y < X\}$ [JTS75, Ton74, Ton75]. R^2 [DH74]. s [Bha73, Lik74]. s^n [AT79]. σ^2 [JMM78]. t [AS73, KP79, Ros75c, SI70, TC72, YM74]. T^2 [BJN71]. T_M^2 [JH79]. V [SC71]. W [GH79, HH73, HL76, Ste78, Tho75]. X [Scl72]. Y [Scl72]. $|X'X|$ [Ano71a, Ano72e, Ano73h, BD71, Dyk71, Eva79].

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Manual [Ziz78]. **Manufactured** [Kao72]. **Many** [Ros75b, Ros77]. **Maps** [J.79l]. **Marc** [Fre73a, J.77a]. **Marcel** [J.79b]. **Mardia** [J.79u, Wat73].
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Markets [Kno71]. **Markov** [Cra74, Sys75, AvdL70, Bri74, JK74, WB71, Doo72, Sys76]. **Marquardt** [SS71b]. **Marvin** [Mye74]. **Mask** [Luc73]. **Massey** [Wei71]. **Material** [BF72, Lev79]. **Mathai** [J.79v, Sim76]. **Mathematical** [Ber73, Bow77, Boy74, Cha75a, Cor71, Eri72, Fre73b, Hac79, Hal77b, Har72, Ing78a, J.75g, J.76h, J.77k, J.78o, Jon76b, Lan73, Sen75, Bis72b, Lac72a].
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Mathematische [Ens77]. **Matrices** [And73, Ban73, GZ79, GC74, Urq73, Zys70, Gow72]. **Matrix** [CGO07, Fra77, Goo70, Haw75, Ray70, Ron77]. **Matter** [Ano70b, Ano70c, Ano70d, Ano70e, Ano70g, Ano70h, Ano70i, Ano70j, Ano71b, Ano71c, Ano71d, Ano71e, Ano71h, Ano71i, Ano71j, Ano71k, Ano72a, Ano72b, Ano72c, Ano72d, Ano72h, Ano72i, Ano72j, Ano72k, Ano73b, Ano73c, Ano73d, Ano73e, Ano73l, Ano73m, Ano73n, Ano73o, Ano74a, Ano74b, Ano74c, Ano74d, Ano74h, Ano74i, Ano74j, Ano74k, Ano75a, Ano75b, Ano75c, Ano75d, Ano75g, Ano75h, Ano75i, Ano75j, Ano76a, Ano76b, Ano76c, Ano76d, Ano76g, Ano76h, Ano76i, Ano76j, Ano77b, Ano77c, Ano77d, Ano77e, Ano77i, Ano77j, Ano77k, Ano77l, Ano78a, Ano78b, Ano78c, Ano78d, Ano78f, Ano78g, Ano78h, Ano78i, Ano78j, Ano79a, Ano79b, Ano79c, Ano79d, Ano79h, Ano79i, Ano79j, Ano79k].
Matters [Ano72e, Ano73h, BD71]. **Maurice** [Fie73, Ger75]. **Maximize** [Ano71a, Dyk71, Eva79]. **Maximum** [AA74, AR79, Ano73k, AR73, BR73, BWL78, Coh65, CS76, Gri72, HH73, HP71, JS76, Lem74, Lem75, Mat78, MN77, SP74, SP77, SB72a, SU79, TBA70].
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McNeil [J.78d]. **Mead** [ON75]. **Mean** [All71, Bad70, Bor72, BH73, CF76, Far75, FKRO71, GW71, Jos72, Kus79, Low74, McL74a, McL74b, ML75, PK79, Vin76, Wan71, HK77, LH77].
Meaning [Mal74, Mar74, BT74]. **Meaningful** [WW78]. **Means** [BF74, CHH⁺71, Fed75, Hah75, Hah77, Lan72, SU79, Ury76, WC70].
Measure [Igl73]. **Measurement** [BR75, Gru73b, Har75, J.79t].
Measurements [TB75]. **Measures** [WW78, Sne70]. **Measuring** [Gru73b, HN70, Han75]. **Median** [Wol77b]. **Medical** [Fle76, Lac72b, Ros75a]. **Meeting** [Ano70a]. **Meltzer** [Hel71b, Jac80]. **Men** [Ens78]. **Mensing** [Gle77]. **Metagames** [Lut73]. **Meters** [Joi77]. **Method**

[All74, And70, And74, Ang74, Aro76, CR79, CBI79, GHW79, Gue77, Hoo79, J.76i, Lin79, OB76, SH79, See70, TW70, Yue78, ZNL79]. **Methoden** [JH73b]. **Methodology** [Dud79, Man73]. **Methods** [Bis72b, Boa79a, BCK61, Con74, Dav77, Dav79b, Dun72, Ehr77, FM71, Goo71, Gri70, HR75, J.76d, J.76e, J.77b, J.79q, J.79b, Jae70, Lac72b, Lan72, Leo70, MBC79, Mer79, Mih75, Mih77, NH72, Pat73, Ran70a, RH78, Sal75b, San72, Sne77, Sto76, Weg72, Zel72, BCK78, And75, Cor71, For71, Gib74, J.78i, J.78f]. **Meyer** [Joh71b]. **Michael** [Car77a, Sie75]. **Micro** [Car77b]. **Micro-Organisms** [Car77b]. **Microbiological** [Car77b]. **Microscale** [Ano73j, Mar73]. **MIL** [BS79, Koy78, Koy79]. **MIL-STD** [BS79]. **MIL-STD-105D** [Koy78, Koy79]. **Milestones** [CGO07]. **Milton** [K.71e]. **Minimal** [AT79]. **Minimization** [ON75]. **Minimizing** [For72]. **Minimum** [BD74, BR73, Dic74, Far75, Hal79, Nád71, NW77, NW79, Sch74a, SA79, Sch76, SLK79, SS78, Tho73, Vin76, WK77, HK77]. **Minimum-Point** [BD74]. **MINITAB** [J.78g]. **Misclassification** [Lac74b, Lac79, McL74a, Sor71, Sor72a, Sor72b, Sor73]. **Misclassified** [Lac74b, McL72, Ten72]. **Missing** [BDH70, HG73, Joh79, Pre71, Rub76, Wat70a]. **Misuse** [Kin79b]. **Mitra** [Ban73]. **MIVQUE** [SS78]. **Mixed** [Beh72, CR79, CS76, DS79, Haw72, HH73, SWD74]. **Mixing** [BR75, Cho79, Luk73]. **Mixture** [Ano76e, Beh70, BF72, Cha79, Cor75, CO75, Cor77, CK79, GK77b, Har79, Joh70c, Joh70b, MS74, Par78b, Ray72, Sch71a, Sne73, SM74, Sne75a, Sne75b]. **Mixtures** [Cor73, Cor79, DS77a, DS77b, Gri70, LC70, SN77, SM76, GK77a]. **Model** [Ano72g, Ano73j, Ant77, BDH70, Bri74, CF77, CS76, Cor77, DS77b, GLV74, Gue71b, HBA71, Hah72, HH73, HP71, Hil78, HJF78, HM73, Leo75, Man71a, Mar73, MW78, MHC77, MPB70, MA78, Nai74, OM72, Par78b, Pas79, Rah76, RR76, SWD70, SB72b, Tar76, TA75, TC73, WK71, WB74, WG78, Wio70, GDF78, J.75d]. **Model-Discrimination** [MPB70]. **Modeling** [LS71b, LSM72, PW77, Sch75]. **Modelling** [MPBD79, J.79m]. **Models** [Ano76e, BK70a, BG78, BL73, Cle71, DS77a, DAH73, Dun74, Fuc78, GK77b, Goo71, Gri79, GPS73, Har73a, Har73b, Hel74, HM77, K.71d, Lac74b, LR76, Lun75, MS74, MW73, Mer72, Par78a, Par78b, Pre75, PDB77, San72, San73, See73, SM74, Sne75b, Sne77, Spr76, Spr78, SWD74, TW72a, Wol78, Boa73, Boa79b, Hul73, J.75a, J.76g, Ron72, Smi77]. **Moderate** [Gut73b, MF77]. **Moderate-Size** [MF77]. **Modern** [Dun77b, Spr78]. **Modes** [Beh70]. **Modification** [Dav79a, Mie74, SOE75]. **Modifications** [Zah75b]. **Modified** [DM78, KM79, Koy78, Lin79, Luc73]. **Modular** [Bod70]. **Modulus** [SU79]. **Molenaar** [Hel71a]. **Moments** [Cha70b, Gro71b, Jae74]. **Monotone** [Sen74]. **Monotonicity** [Gro71b]. **Monte** [Rel70]. **Montgomery** [Dun77a]. **Moore** [Hub78]. **Morris** [Kin78, Ran70b, Win71]. **Morrison** [J.78e]. **Mortality** [MS73]. **Most** [Ala71, Bli72, EB77b]. **Mosteller** [Lac74a, Qua75, Odo77]. **MOSUMS** [BH78]. **Motion** [CF76, Nád73, PK76, Ser73, SS74]. **Motions** [HM73]. **Moving** [CK75, RH78, Ste72b, SWD74, Wic72]. **MR** [Kit81].

MTBF [BS79]. **Mullen** [Sch74b]. **Multi** [Coh75, HP71, Sac72]. **Multi-Censored** [Coh75]. **Multi-Level** [Sac72]. **Multi-Risk** [HP71]. **Multicollinearity** [WW78]. **Multicomponent** [SCSB76]. **Multidimensional** [CR79, Goo71]. **Multifunctional** [Sac76]. **Multinomial** [AA74, Ang74, BK70b, OL77, Ten72]. **Multinormal** [HS72]. **Multiple** [Ait74, And74, Bea70, FH79, Goo71, Gor76, HG73, Haw72, LSYF79, SP74, SU79, Ury76, VM79, WB71, Cle72a, J.77g, J.78h]. **Multiplicative** [SOE75, YC78]. **Multiresponse** [BDH70, BHME73, Gri73, MPBD79]. **Multivariate** [BMP77, Cha79, Dun72, Fre74a, Gaf78, GG70a, Gut73a, HB71, J.78f, J.79i, McK79, Mil72b, Odo77, Pat73, Reg76, Ron77, Ger75, J.75c, J.76d, J.76e, J.77h, K.74c, Kha74, O'F73]. **Murdoch** [J.78p]. **Muse** [Ano79e]. **Mutually** [BCK61, Hed71, BCK78]. **Myers** [Rus73, Fed74a, Man73]. **Myint** [Cha75a]. **Myint-U** [Cha75a].

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DY70, Eva71, Fau70, Fra77, Hal77a, Haw72, HK75, JK71, Kap72, Ken71, Lac79, MH72, MW75a, Ng76, Sch70, SS71a, Sne71, Tho75, Ton74, Ton75, JTS75].
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O [Hac78, HH73, Ron72, Ros75a, Sie75, Sne74]. **Objectives** [J.78b]. **Objects** [Ens76]. **Observable** [Nád70a]. **Observation** [Coo77, Joh70c, Joh70b, KS71, Lik74]. **Observations** [Ano73g, FM77, GB72, Joh70c, Joh70b, Man70a, Ray72, Sin71, TS79, BN72, HP73, Fre75, J.78f].
Observed [FB75, Har74]. **Obstructive** [Ens78]. **Obtain** [Gre70a].
Obtained [Sin71]. **Obtaining** [CK79, Gue77, Jae70, MF73]. **OC** [Kow71].
O'Carroll [J.79m]. **Occurrence** [Gre70b, Sap73]. **Odeh** [J.76g, J.78l, J.77k, J.78o]. **Odell** [Gow72, Ron72]. **Odoroff** [Ano77a, Ano79f]. **Olkin** [Dud79, Sid75]. **O'Muircheartaigh** [J.77m]. **One** [Bai73, FM77, GLV74, GPU76, HP73, Hoc72, JD78, KB75, Kus79, Lad77, MD71, McM71, MM73, Rah76, SS75, SD77, Wes71, Boa79a]. **One-Four** [Boa79a]. **One-Sided** [FM77, SS75, Wes71, GPU76, HP73]. **One-Way** [Kus79]. **Only** [CHH⁺71, Nád70a]. **Operates** [DY70]. **Operating** [BM76, Ell76, PW77, SLK79]. **Operation** [And70, Wan71]. **Operational** [J.79n]. **Operations** [J.77a]. **Opinion** [Gle78]. **Optimal** [Ano77h, BN72, Bis72b, BH77, EB78a, Gor76, Gre70a, Har74, J.79d, Jon76a, Krz77, Luc78, Mac76, MW78, MCM75, Mit74a, Mit74b, MB78a, MB78b, Sim73, Sor72a, SC71, Gor76, J.77i, Ran70b]. **Optimality** [NGM70, SD75].
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Orbital [Bus71]. **Order** [Ber72a, BMH76, BD74, Gue77, Hed71, Hok74, JC76, Kal75, Kam72, Kam74, Mit74b, OM72, Qua75, SWD70, SWD74, TW72b, Weg74, Gru71a]. **Ordered** [Lik74, Man70a, Ode71]. **Ordering** [Dud79, Gar71]. **Orders** [Dic74].
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Transformation [BH74, Cha79, GH79, HH73, Tho75, WY78].
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Transient [BGH73]. **Transients** [Bri73b]. **Transition** [WB74]. **Treatment**
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 [MHL77a, MHL77b]. **Triple** [Pat76b]. **Trirogoff** [Bis72b]. **trivariate** [TC72].
Truncated
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Truncation [Man75]. **Truth** [Bon76b, Bon77]. **Tsokos** [J.77n, Zac74].
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 Cho79, Dan78, DM77, DL70, DAH73, Dun78c, EB74, EB75, EB78c, EB79,
 GW75, Gri70, Gru71c, Hah77, HW75, Har73a, HJ76, Jae70, Jae76, Joh70c,
 Joh70b, JD78, Kam74, KB75, KP71, Law77a, Leo70, LO79, Lik74, Low76,

Man72, MF75a, MDM77, McK76, MD71, McM71, MPB70, MM73, MA78, Nea70, Pie73, Ray72, Sal75b, Sam78, SG71, SS76, SdV73, TW72b, Tho73, TA75, Var70, WB74, Web71, WDFH73, Wol77b, AB71, GPU76, And75].

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[WG78]. **Vincze** [J75e]. **Vinod** [HK77]. **Virginia** [Hei76]. **Visual**
[San72, San73]. **Vital** [Car77a]. **Vocabulary** [Dil71]. **Vol**
[J.75g, J.76h, J.78o]. **Volume** [Ano70o, Ano71l, Ano72l, Ano73p, Ano74l,
Ano75l, Ano76o, Ano77q, Ano78o, Ano78p, Ano79p, Bor72, Cra74, Fre73b,
Har72, J.77k, J.79q, J.79g, J.79f, K.71d, K.73b, K.73a, Lac71b, Sne74].
VOQL [Hal79]. **Vote** [Ano75m]. **vs** [LW71, MF75a, Scl72].

W [Add72, Add79, Ano74e, Bha72, Boy74, Dav70, Fre73a, Fre73c, Gle77,
GH75, Hay73, Hea78, Hel71a, Hub78, J.76d, J.76e, J.76a, J.77d, J.77f, J.77e,
J.77o, J.77q, J.77p, J.78n, J.78l, K.73d, Lac71b, Lac74a, Lan75, Law75b,
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[Fed74a, Dye74, Har77]. **Wani** [Gol74]. **Wasan** [Rog70a]. **Water**
[K.74a, Ven70]. **Watts** [Ano75f, Ran70c]. **Way**
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Wayne [McC78b]. **Weak** [Ber72b]. **Weather** [Dav79a, Mie74, SOE75].

Weibull

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Coh75, D'A71a, D'A71b, Dan70, DA73, EB73, EB74, Eng75, EB75, EB77a,
EB78b, EB79, Fal70, Fin76, Gro71b, HBA71, KARR75, Law73, Law75a,
Law78, LL78, Lem75, Man70a, Man71b, Man72, MF73, MF75a, MF75b,
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Weights [GZ79]. **Weischedel** [Gor76]. **Welch** [Ros75c]. **Wetherill**

[Boa79a, Ehr77, Tsi78]. **Wheeler** [J.76b]. **Where** [Sar71]. **Whether** [Leo70].

Which

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White [Ano80b]. **Whitehouse** [Mar75]. **Whittemore** [J.79h]. **Wide**

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[Kin79b]. **Winsorized** [MHL77a, YF76]. **Wiorowski** [Cro71]. **Within**

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[Ano74e]. **Wonnacott** [Bow78, Bow78]. **Wood** [Sne72a]. **Work** [Buc73].

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